


<b>Search Notes</b>  	<b>Application/Control No.</b>  10582150	<b>Applicant(s)/Patent Under Reexamination</b>  HIPP, IMRE
	<b>Examiner</b>  HOON J CHUNG	<b>Art Unit</b>  2416

SEARCHED			
Class	Subclass	Date	Examiner
370	204-205, 516-520	05/04/2009	HJC
375	356, 362, 364, 373, 375, 377	05/04/2009	HJC

SEARCH NOTES		
Search Notes	Date	Examiner
Double Patenting	05/04/2009	HJC
EAST (PLL, reference clock, TDM, etc.)	05/04/2009	HJC
	05/05/2009	
Google (PLL, reference clock, synchronization, etc.)	05/04/2009	HJC
Consulted an examiner (Habte Mered)	05/04/2009	HJC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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